Abstracts

A Measurement Method for Accurate Characterization and Modeling of MESFET Chips

D.E. Peck and D.F. Peterson. "A Measurement Method for Accurate Characterization and Modeling of MESFET Chips." 1981 MTT-S International Microwave Symposium Digest 81.1 (1981 [MWSYM]): 310-312.

A straightforward measurement procedure based on a deembedding method and FET unbiased drain RF measurements is presented that produces accurate chip MESFET characteristics. Usefulness of the data is shown by inexpensively obtained MESFET model parameters.

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